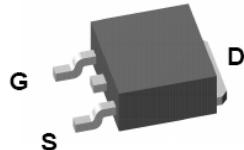


P6010DDG

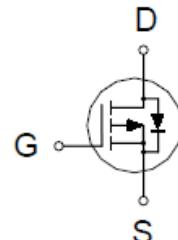
P-Channel Logic Level Enhancement Mode MOSFET

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
-100V	60mΩ @ $V_{GS} = -10V$	-20A



TO-252



ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ C$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	-100	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current $T_C = 25^\circ C$	I_D	-20	A
		-12	
Pulsed Drain Current ¹	I_{DM}	-60	
Avalanche Current	I_{AS}	-54	
Avalanche Energy	E_{AS}	149	mJ
Power Dissipation $T_C = 25^\circ C$	P_D	50	W
		20	
Operating Junction & Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$	2.5	75	°C / W
Junction-to-Ambient	$R_{\theta JA}$			

¹Pulse width limited by maximum junction temperature.

P6010DDG

P-Channel Logic Level Enhancement Mode MOSFET

ELECTRICAL CHARACTERISTICS ($T_J = 25^\circ\text{C}$, Unless Otherwise Noted)

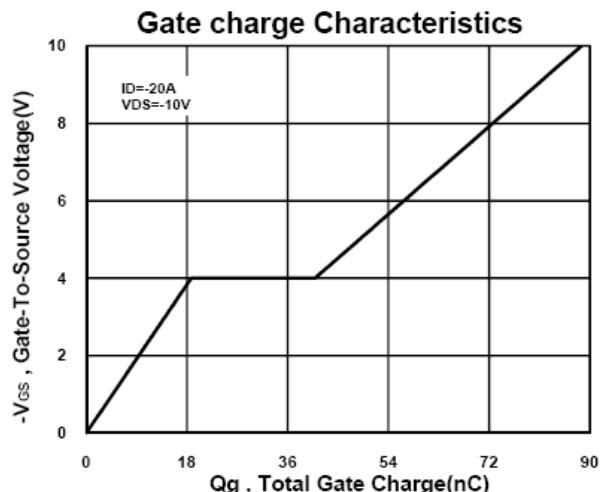
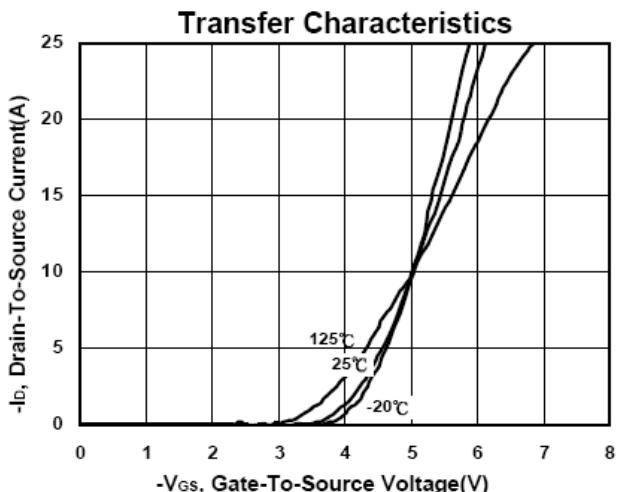
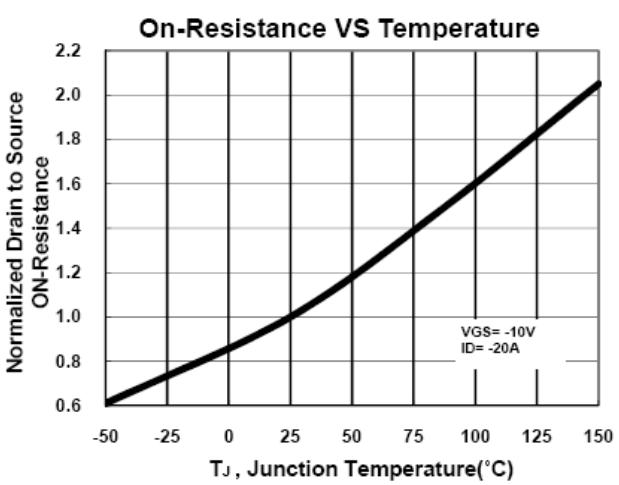
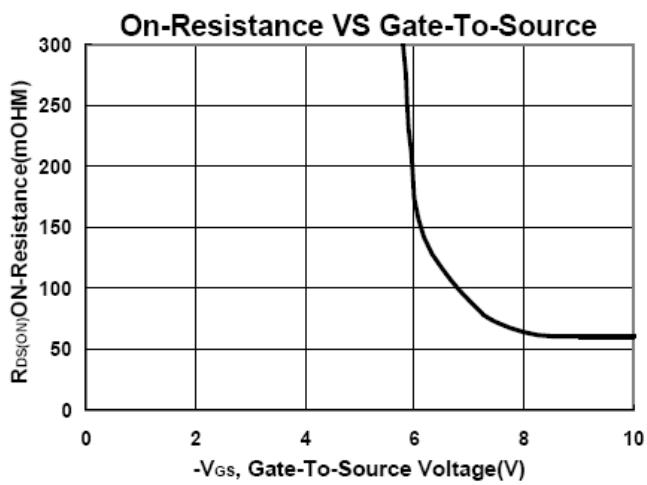
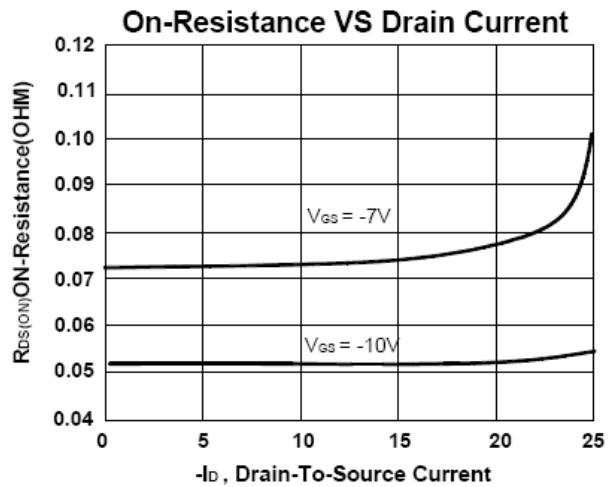
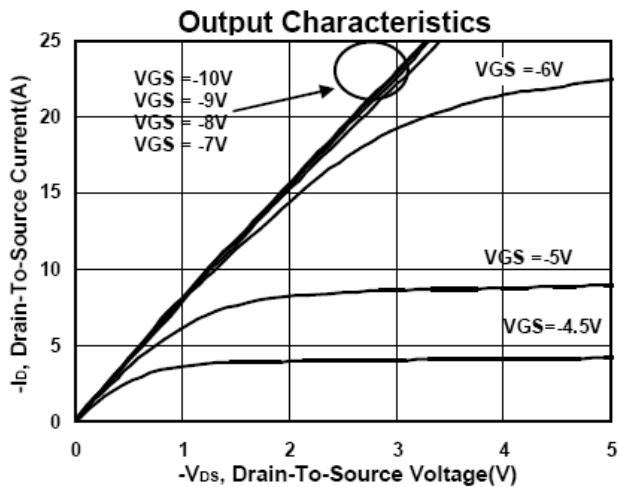
PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = -250\mu\text{A}$	-100			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = -250\mu\text{A}$	-1.5	-2.7	-4	
Gate-Body Leakage	I_{GSS}	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			± 250	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = -80\text{V}, V_{\text{GS}} = 0\text{V}$			-1	μA
		$V_{\text{DS}} = -80\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			-10	
On-State Drain Current ¹	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = -5\text{V}, V_{\text{GS}} = -10\text{V}$	-60			A
Drain-Source On-State Resistance ¹	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = -7\text{V}, I_D = -18\text{A}$		53	72	$\text{m}\Omega$
		$V_{\text{GS}} = -10\text{V}, I_D = -20\text{A}$		51	60	
Forward Transconductance ¹	g_{fs}	$V_{\text{DS}} = -5\text{V}, I_D = -20\text{A}$		35		S
DYNAMIC						
Input Capacitance	C_{iss}	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = -25\text{V}, f = 1\text{MHz}$		4960		pF
Output Capacitance	C_{oss}			224		
Reverse Transfer Capacitance	C_{rss}			167		
Gate Resistance	R_g	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		4.6		Ω
Total Gate Charge ²	Q_g	$V_{\text{DS}} = 0.5V_{(\text{BR})\text{DSS}}, V_{\text{GS}} = -10\text{V}, I_D = -20\text{A}$		90		nC
Gate-Source Charge ²	Q_{gs}			19		
Gate-Drain Charge ²	Q_{gd}			24		
Turn-On Delay Time ²	$t_{\text{d}(\text{on})}$	$V_{\text{DS}} = -20\text{V}, I_D \approx -1\text{A}, V_{\text{GS}} = -10\text{V}, R_{\text{GS}} = 6\Omega$		20		nS
Rise Time ²	t_r			25		
Turn-Off Delay Time ²	$t_{\text{d}(\text{off})}$			120		
Fall Time ²	t_f			125		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS ($T_J = 25^\circ\text{C}$)						
Continuous Current	I_S				-20	A
Forward Voltage ¹	V_{SD}	$I_F = -20\text{A}, V_{\text{GS}} = 0\text{V}$			-1.3	V
Reverse Recovery Time	t_{rr}	$I_F = -20\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		84.3		nS
Reverse Recovery Charge	Q_{rr}			256		nC

¹Pulse test : Pulse Width $\leq 300\ \mu\text{sec}$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

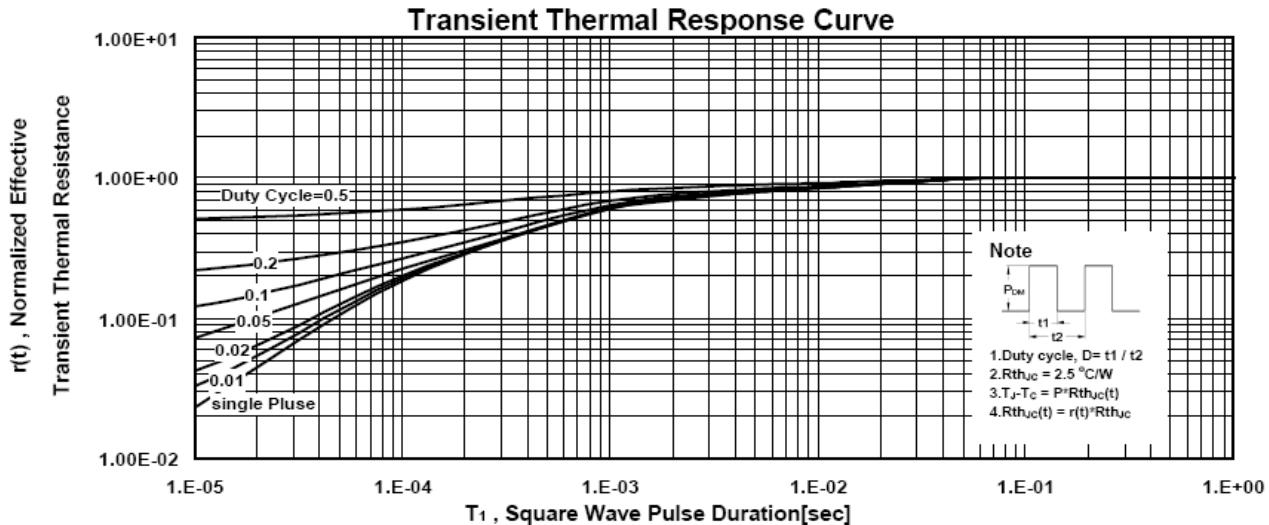
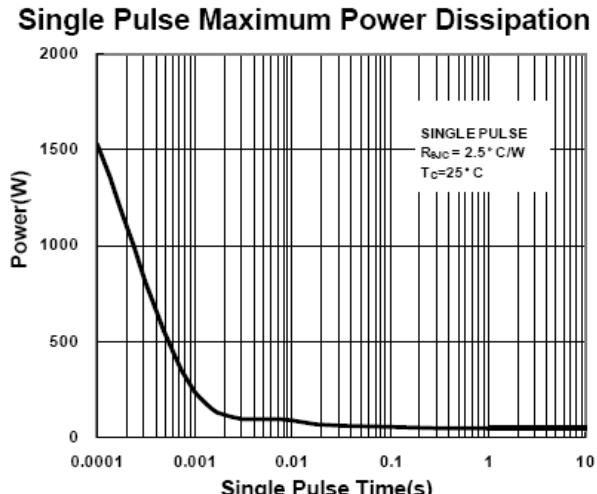
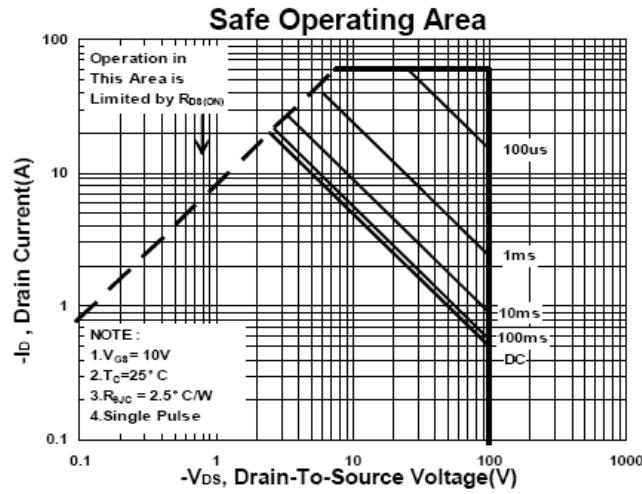
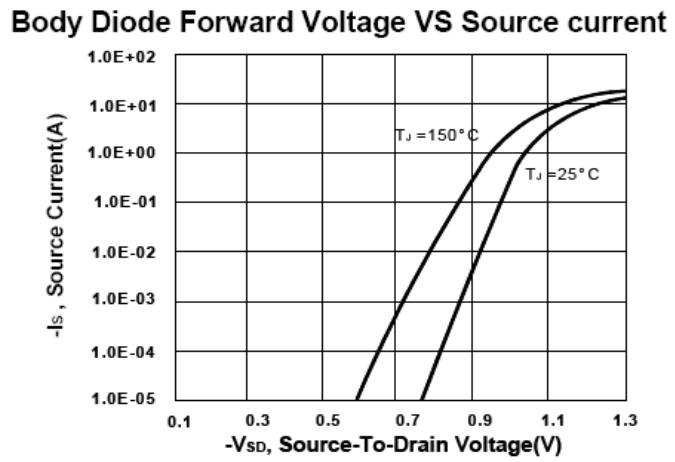
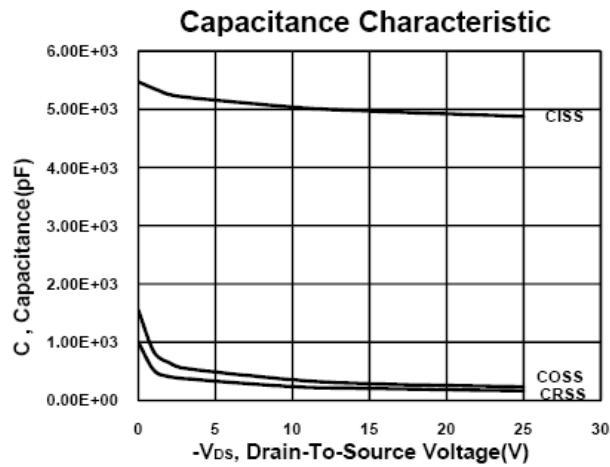
P6010DDG

P-Channel Logic Level Enhancement Mode MOSFET



P6010DDG

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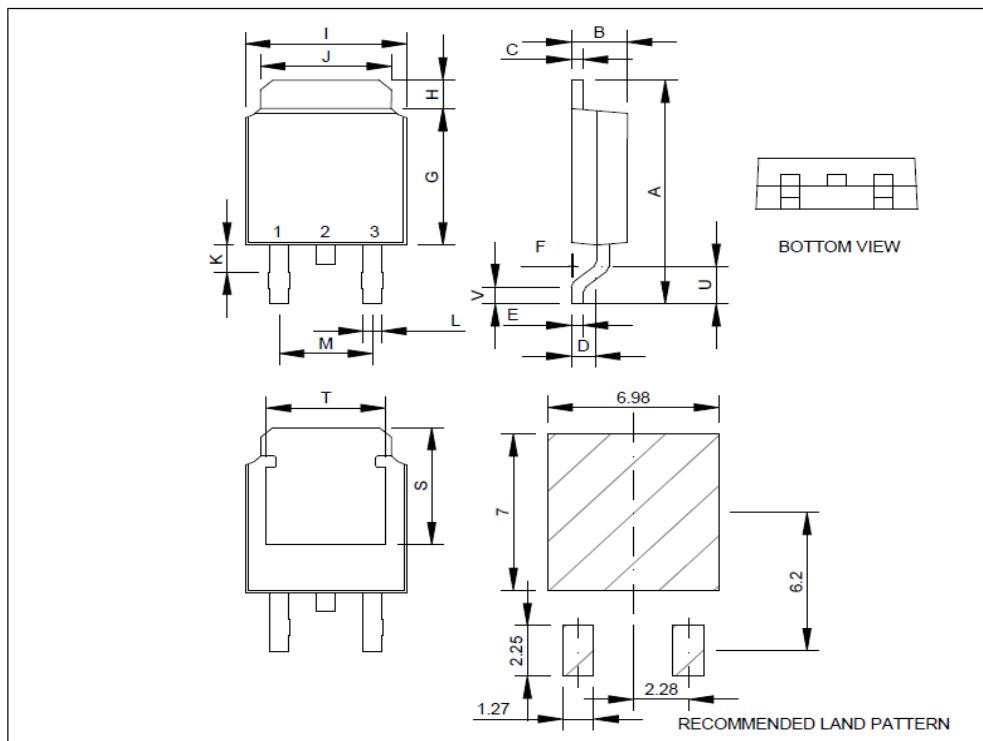
P6010DDG

P-Channel Logic Level Enhancement Mode MOSFET

Package Dimension

TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	8.9	10	10.41	J	4.8		5.64
B	2.1	2.2	2.4	K	0.15		1.1
C	0.4	0.5	0.61	L	0.4	0.76	0.89
D	0.82	1.2	1.5	M	4.2	4.58	5
E	0.4	0.5	0.61	S	4.9	5.1	5.3
F	0		0.2	T	4.6	4.75	5.44
G	5.3	6.1	6.3	U	1.4		1.78
H	0.9		1.7	V	0.55	1.25	1.7
I	6.3	6.5	6.8				



*因为各家封装模具不同而外观略有差异，不影响电性及Layout。